Notice of References Cited Application/Control No. 10/661,154 Examiner Mike Nguyen Applicant(s)/Patent Under Reexamination INNAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,044,444	03-2000	Ofek, Yuval	711/162
	В	US-6,108,748	08-2000	Ofek et al.	711/112
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0		,			
	Р					
	α					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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